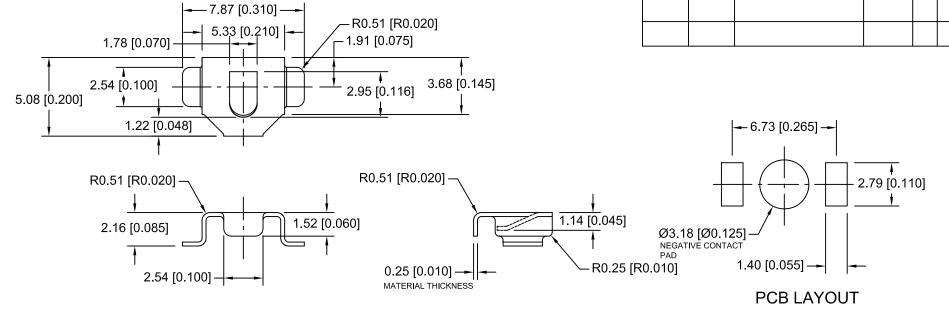
Date	SYM	REVISION RECORD	AUTH	DR.	CK.
5/22/09	Α	ADDED TEST RESULTS	T.B.	B.S.	
09/09/11	В	ADDED PCB LAYOUT	T.B.	B.S.	
09/30/11	С	ADDED NEG. CONT. PAD	T.B.	B.S.	



NOTES:

1. MATERIAL:

0.25mm PHOSPHOR BRONZE 1/2H, NICKLE PLATED 40U"-120U"

TEMPERATURE RANGE: -40°C TO +270°C

- * VIBRATION TEST: 10-50-10 HZ SWEEPED IN 60 SECONDS X,Y,Z DIRECTION: 1 HOUR EACH DIRECTION
- * RESULT: NO DISLODGEMENT OF THE CELL OR DAMAGE NO DISCONTINUITY OVER 10 MICRO-SECONDS
- * SHOCK TEST: HALF SINE WAVE ACCELERATION 150G. 6 MICRO-SECONDS
 3 SHOCK PULSES EACH DIRECTION PER AXIS. TOTAL OF 18 PULSES
- * RESULT: NO EVIDENCE OF PHYSICAL DAMAGE
- * DROP TEST: DROPED FROM 1M HIGH TO CONCRETE FLOOR
- * RESULT: NO EVIDENCE OF PHYSICAL DAMAGE

ROHS COMPLIANT

Tolerance	Mem	Memory Protection Devices, Inc					
(Except as noted)		200 Broad Hollow Road, Farmingdale, New York 11735					
decimal			Scale	Drawn By B.S.			
±.5 (.020)				Approved By T.B.			
Fractional	Title						
± .8 (.030)	ML414 BATTERY CONTACT						
Angular	Date	Drawing Nu	ımber				
± 3°	09/30/11	BK-414					